ELEG 340 - Fall 08 Solid-State Electronics Quiz 2

9 October 2008

NAME Solution

Time Limit: 30 minutes

Closed Books and Notes. You may use your own calculator, but you may not loan or borrow calculators (ask proctor if you have questions). Put expression in a final form as best you can, and indicate final units (dimensions).

Guidelines:

- I. Full credit requires giving the final dimensions/ units for all numerical quantities that you calculate.
- II. Show all work and calculations for full credit.
- III. Accuracy to 2 significant figures is sufficient.
- IV. Assume that the material is silicon at room temperature (300 K or 296 K), unless otherwise stated.
- V. At room temperature (300K), thermal energy $k_BT = 0.0258$ eV (0.026 eV), silicon has intrinsic concentration $n_i = 1$ (or 1.5) x 10^{10} cm⁻³. and recombination lifetimes: τ_n , $\tau_p = 1$ µsec.

Note permittivity of free space $\varepsilon_0 = 8.85 \text{x} 10^{-14} \text{ F/cm}$; magnitude of electron charge $q = 1.6 \text{x} 10^{-19} \text{ Coul}$

VI. Equations:

$$\begin{split} p_{op} &= ihd/dx & f_{FD}(E) = 1/[1 + exp(E-E_F)/k_BT] \\ n &= n_i exp[(E_F-E_i)/k_BT]. & p &= n_i exp[(E_i-E_F)/k_BT] \\ J_n &= q\mu_n n \mathcal{E} + q D_n dn/dx & J_p &= q\mu_p p \mathcal{E} - q D_p dp/dx \\ U_n &= (n_p - n_{po})/\tau_n & U_p &= (p_n - p_{no})/\tau_p \\ C &= \epsilon_s /W & D/\mu &= k_B T/q & L &= \sqrt{(D\tau)} & E &= Q V \\ \partial p/\partial t &= -1/q \ \partial J_p/\partial x - p'/\tau_p & \partial n/\partial t &= -1/q \ \partial J_n/\partial x - n'/\tau_n \\ \partial p/\partial t &= D_p \ \partial^2 p/\partial x^2 - p'/\tau_p & \partial n/\partial t &= D_n \ \partial^2 n/\partial x^2 - n'/\tau_n \\ p' &= p - p_o &= g_{opt} \tau_p & n' &= n - n_o &= g_{opt} \tau_n \end{split}$$

1. An electron has a kinetic energy of 2 eV (electron volt). What is its energy in Joules? For full credit, show your work.

$$W = gV = 1.6 \times 10^{-19} \text{Conl} \times 2V$$

2eV = 3.2 $\times 10^{-19} \text{Toule}$.

2. A sample of silicon at room temperature (300K) is uniformly doped with acceptors to a concentration $N_A = 10^{18}$ cm⁻³. What is the concentration of holes in the valence band?

3. The silicon in the question above is now compensation doped with donors $N_D = 2x10^{17}$ cm⁻³. What is the new concentration of holes?

4. A wafer of silicon at T = 300 K has a free electron concentration of $n = 1 \times 10^{17} \text{ cm}^{-3}$. What is the hole concentration?

$$P = \frac{n.2}{n} = \frac{10^{20} \text{ cm}^{-6}}{10^{17} \text{ cm}^{-3}} = 10^{3} \text{ cm}^{-3}$$

5. For the silicon above, calculate the energy of the Fermi level, E_F relative to the intrinsic level, E_i.

$$h = 10^{17} \text{cm}^{-3} = n_i \quad \text{EF-Ei)/kT}$$

$$Y = \text{EF-Ei} = \text{kT ln } \frac{10^{17}}{10^{10}} = 6.026 \, \text{ln } 10^7$$

$$7 \times 2.3 = 16.1$$

$$= 0.26 \times 1.61 = 0.26 + 0.15$$

$$= 0.41 \, \text{eV}$$

6. A sample of GaAs is n-type doped with $N_D = 1 \times 10^{16}$ cm⁻³. The electron mobility is $\mu_n = 8500$ cm²/V-s. Calculate the electrical conductivity, σ .

$$C = ng\mu = 10^{16} \text{cm}^{-3} \times 1.610^{-19} \text{C} \times 8.510^{3} \frac{\text{cm}^{2}}{\text{V-S}}$$

$$= 8.5 \times 1.6 \text{ S/cm}$$

$$C = 14 \text{ S/cm}$$

7. A piece of silicon at room temperature (300K) is doped with donors to $N_D = 10^{17}$ cm⁻³. The sample is uniformly illuminated with a generation rate of EHPs: $g_{opt} = 10^{22}$ cm⁻³s⁻¹. (a) what is the excess carrier concentration p' (or n')? (b) what is the *total* concentration of electrons? (c) what is the *total* concentration of holes?

(a)
$$h' = p' = S_{opt} T_n = 10^{22} - 3^{-1} \times 10^{-6} S_{ex}$$

= $10^{16} cm^{-3}$

$$b) n = n_0 + n' = N_0 + n' = 10^{17} \text{ cm}^{-3} + 10^{16} \text{ cm}^{-3}$$

$$= 1.1 \times 10^{17} \text{ cm}^{-3}$$

c)
$$p_0 = \frac{n \cdot 2}{N_b} = \frac{10^{20} \text{ cm}^{-6}}{10^{17}} = 10^3 \text{ cm}^{-3}$$

$$P = P_0 + P' = 10^3 \text{ cm}^2 + 10^{16} \text{ m}^{-3}$$

= 16^{16} cm^{-3}